

## —Micro/Nano 2007 MEMS Forum (Standardization Session)

### (1) Purpose

The Micromachine Center actively promotes international standardization in the MEMS industry in Japan to ensure that MEMS terminology and thin film material tensile test methods meet international standards.

At Micro/Nano 2007, a MEMS Forum International Standardization Session will be held to introduce and discuss the use of the MEMS terminology and thin film material tensile test methods that have been published as international standards. The purpose of the session is to provide information on international standardization activities and promote further strategic progress in efforts at international standardization in the MEMS industry in Japan.

### (2) Program

Micro/Nano 2007 MEMS Forum <b>International Standardization Session</b> —Using MEMS International Standards—		
<b>Date &amp; time:</b> Friday, July 27, 2007 10:00 a.m. - noon <b>Venue:</b> Tokyo Big Sight (special venue set up within West No. 3 Hall) <b>Sponsor:</b> Micromachine Center (Standardization Project Committee) / MEMS Industry Forum <b>Admission fee:</b> Free		
MC: Noriyuki Kenmotsu, Micromachine Center		
10 : 00 – 10 : 05	<b>Welcome</b>	Naotake Oyama, Chairman, Standardization Project Committee, Micromachine Center
10 : 05 – 10 : 20	<b>International Standardization Policies of the Ministry of Economy, Trade and Industry</b>	Akira Izumi, Director, Electronic Standardization Promotion Office, Industrial Technology Environment Bureau, Ministry of Economy, Trade and Industry (METI)
10 : 20 – 10 : 45	<b>MEMS International Standardization Trends and Roadmap to Standardization</b>	Kuniki Owada, Representative, International Standardization Engineering Laboratory Professor, Department of Information Science, College of Science and Engineering, Teikyo University
10 : 45 – 11 : 10	<b>Overview of MEMS Terminology</b>	Moronuki Nobuyuki, Professor, Faculty of System Design, Tokyo Metropolitan University
11 : 10 – 11 : 35	<b>Overview of Tensile Test Methods and Standard Test Specimen Standards</b>	Kazuki Takashima, Professor, Materials Engineering, Department of Natural Science Research, Graduate School of Science and Technology, Kumamoto University
11 : 35 – 11 : 55	<b>Efforts at International Standardization of Test Equipment (From a Test Equipment Manufacturer's Perspective)</b>	Tadashi Hasegawa, Testing & Measurement Group, Applied Technology Department, Analytical Equipment Division, Shimadzu Corporation
11 : 55 – 12 : 00	<b>Closing</b>	Keiichi Aoyagi, Executive Director, Micromachine Center

Access Map

